

IEEE EDS Kansai Chapter Awards 2021

■ IEEE EDS Kansai Chapter of the Year Award

Author: **Yoshihiro Sato**¹

Title: Characterization Scheme for Plasma-Induced Defect Creation due to Stochastic Lateral Stragglings in Si Substrates for Ultra-low Leakage Devices [IEDM]

Coauthors: T. Yamada¹, K. Nishimura¹, M. Yamasaki¹, M. Murakami¹, K. Urabe², and K. Eriguchi²

Affiliation: ¹Panasonic, ²Kyoto University

■ IEEE EDS Kansai Chapter MFSK Award (Student Award)

Author: **Kazuki Monta**¹,

Title: Secure 3D CMOS Chip Stacks with Backside Buried Metal Power Delivery Networks for Distributed Decoupling Capacitance [IEDM]

Coauthors: Hiroki Sonoda¹, Takaaki Okidono², Yuuki Araga³, Naoya Watanabe³, Haruo Shimamoto³, Katsuya Kikuchi³, Noriyuki Miura⁴, Takuji Miki¹ and Makoto Nagata¹

Affiliation: ¹Kobe University, ²ECSEC, ³AIST, ⁴Osaka University